



Welcome to [E-XFL.COM](https://www.e-xfl.com)

What is "[Embedded - Microcontrollers](#)"?

"[Embedded - Microcontrollers](#)" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "[Embedded - Microcontrollers](#)"

Details

Product Status	Not For New Designs
Core Processor	M16C/60
Core Size	16-Bit
Speed	20MHz
Connectivity	EBI/EMI, I ² C, SIO, UART/USART
Peripherals	DMA, LVD, POR, PWM, WDT
Number of I/O	85
Program Memory Size	512KB (512K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	31K x 8
Voltage - Supply (Vcc/Vdd)	1.8V ~ 5.5V
Data Converters	A/D 26x10b; D/A 2x8b
Oscillator Type	Internal
Operating Temperature	-20°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	100-BQFP
Supplier Device Package	100-QFP (14x20)
Purchase URL	https://www.e-xfl.com/product-detail/renesas-electronics-america/r5f363amnfa-u0

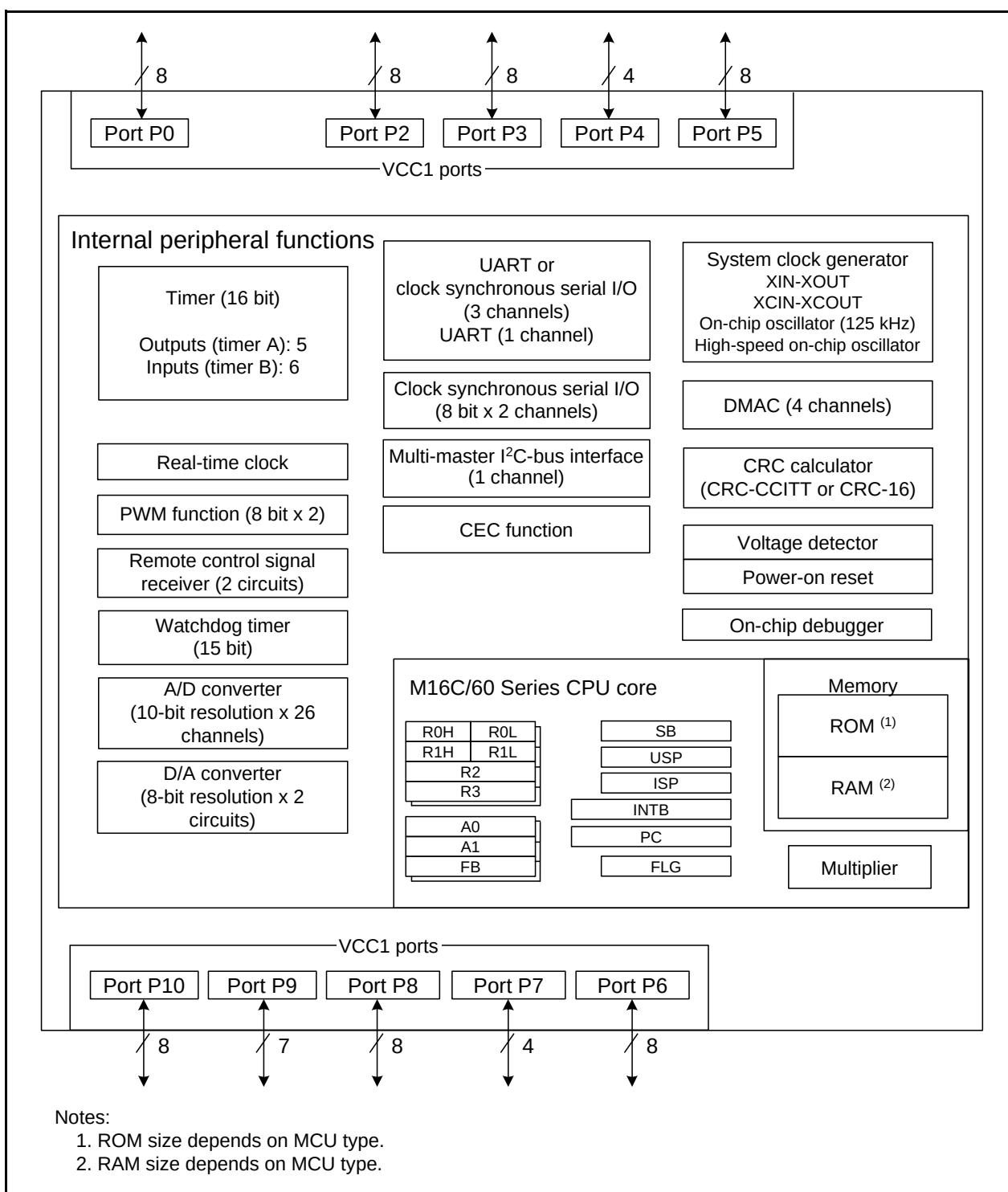


Figure 1.5 Block Diagram for the 80-Pin Package

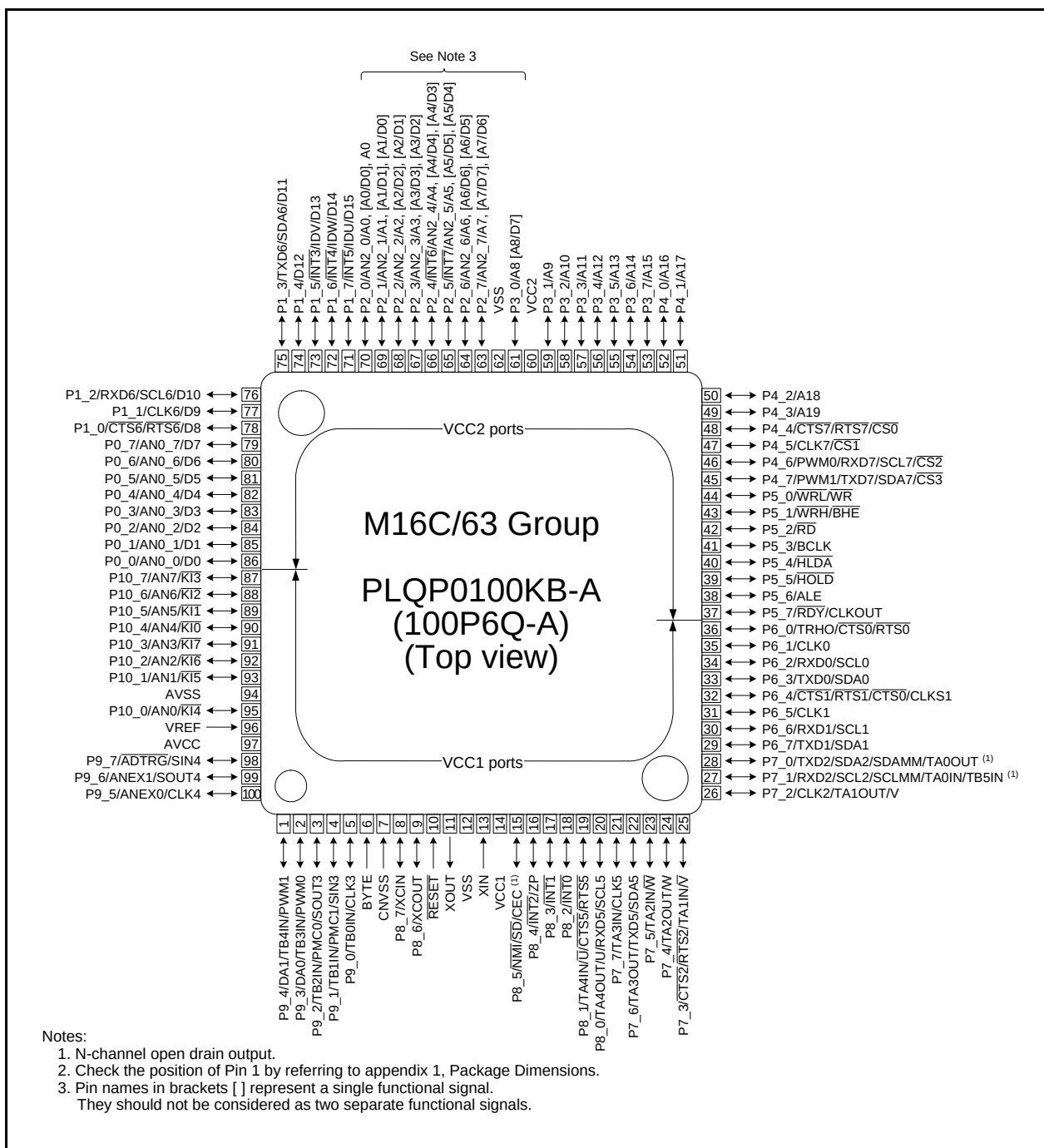


Figure 1.7 Pin Assignment for the 100-Pin Package

Table 1.13 Pin Functions for the 80-Pin Package (1/2)

Signal Name	Pin Name	I/O	Power Supply	Description
Power supply input	VCC1, VSS	I	-	Apply 1.8 to 5.5 V to the VCC1 pin and 0 V to the VSS pin.
Analog power supply input	AVCC, AVSS	I	VCC1	This is the power supply for the A/D and D/A converters. Connect the AVCC pin to VCC1, and connect the AVSS pin to VSS.
Reset input	$\overline{\text{RESET}}$	I	VCC1	Driving this pin low resets the MCU.
CNVSS	CNVSS	I	VCC1	Input pin to switch processor modes. After a reset, to start operating in single-chip mode, connect the CNVSS pin to VSS via a resistor.
Main clock input	XIN	I	VCC1	I/O pins for the main clock oscillator. Connect a ceramic resonator or crystal between pins XIN and XOUT. ⁽¹⁾ Input an external clock to XIN pin and leave XOUT pin open.
Main clock output	XOUT	O	VCC1	
Sub clock input	XCIN	I	VCC1	I/O pins for a sub clock oscillator. Connect a crystal between XCIN pin and XCOU pin. ⁽¹⁾ Input an external clock to XCIN pin and leave XCOU pin open.
Sub clock output	XCOU	O	VCC1	
Clock output	CLKOUT	O	VCC1	Outputs a clock with the same frequency as f _C , f ₁ , f ₈ , or f ₃₂ .
$\overline{\text{INT}}$ interrupt input	$\overline{\text{INT0}}$ to $\overline{\text{INT2}}$	I	VCC1	Input for the $\overline{\text{INT}}$ interrupt.
	$\overline{\text{INT6}}$, $\overline{\text{INT7}}$	I	VCC1	
$\overline{\text{NMI}}$ interrupt input	$\overline{\text{NMI}}$	I	VCC1	Input for the $\overline{\text{NMI}}$ interrupt.
Key input interrupt input	$\overline{\text{KI0}}$ to $\overline{\text{KI7}}$	I	VCC1	Input for the key input interrupt.
Timer A	TA0OUT, TA3OUT, TA4OUT	I/O	VCC1	I/O for timers A0, A3, and A4 (TA0OUT is N-channel open drain output).
	TA0IN, TA3IN, TA4IN	I	VCC1	Input for timers A0, A3, and A4.
	ZP	I	VCC1	Input for Z-phase.
Timer B	TB0IN, TB2IN to TB5IN	I	VCC1	Input for timers B0, and B2 to B5.
Real-time clock output	TRHO	O	VCC1	Output for the real-time clock.
PWM output	PWM0, PWM1	O	VCC1	PWM output.
Remote control signal receiver input	PMC0	I	VCC1	Input for the remote control signal receiver.

Note:

1. Contact the manufacturer of crystal/ceramic resonator regarding oscillation characteristics.

3.3 Accessible Area in Each Mode

Areas that can be accessed vary depending on processor mode and the status of each control bit. Figure 3.3 shows the Accessible Area in Each Mode.

In single-chip mode, the SFRs, internal RAM, and internal ROM can be accessed.

In memory expansion mode, the SFRs, internal RAM, internal ROM, and external areas can be accessed. Address space is expandable to 4 MB with the memory area expansion function.

In microprocessor mode, the SFRs, internal RAM, and external areas can be accessed. Address space is expandable to 4 MB with the memory area expansion function. Allocate ROM to the fixed vector table from FFFDCh to FFFFFh.

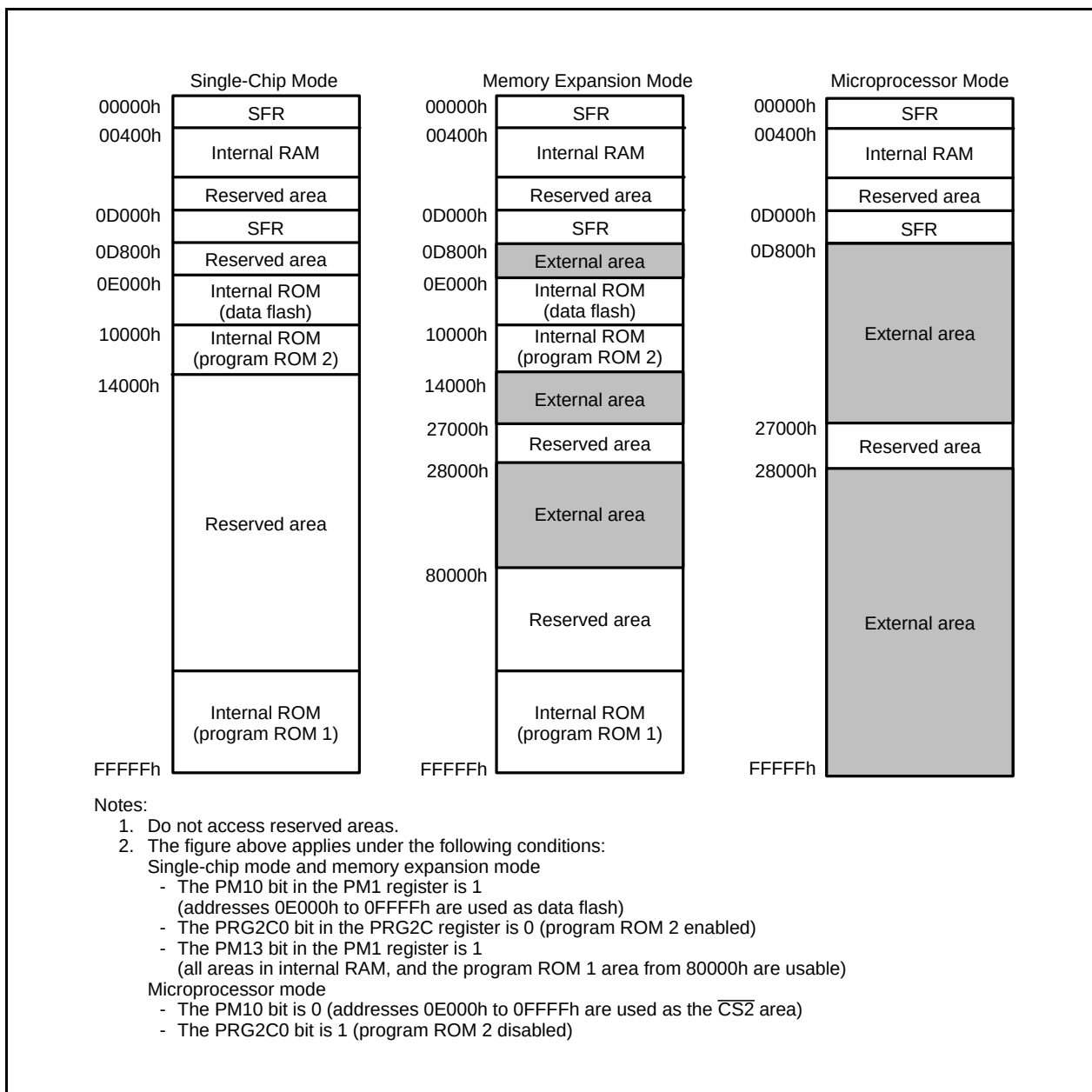


Figure 3.3 Accessible Area in Each Mode

Table 4.9 SFR Information (9) ⁽¹⁾

Address	Register	Symbol	Reset Value
0240h			
0241h			
0242h			
0243h			
0244h	UART0 Special Mode Register 4	U0SMR4	00h
0245h	UART0 Special Mode Register 3	U0SMR3	000X 0X0Xb
0246h	UART0 Special Mode Register 2	U0SMR2	X000 0000b
0247h	UART0 Special Mode Register	U0SMR	X000 0000b
0248h	UART0 Transmit/Receive Mode Register	U0MR	00h
0249h	UART0 Bit Rate Register	U0BRG	XXh
024Ah	UART0 Transmit Buffer Register	U0TB	XXh
024Bh			XXh
024Ch	UART0 Transmit/Receive Control Register 0	U0C0	0000 1000b
024Dh	UART0 Transmit/Receive Control Register 1	U0C1	00XX 0010b
024Eh	UART0 Receive Buffer Register	U0RB	XXh
024Fh			XXh
0250h	UART Transmit/Receive Control Register 2	UCON	X000 0000b
0251h			
0252h	UART Clock Select Register	UCLKSEL0	X0h
0253h			
0254h	UART1 Special Mode Register 4	U1SMR4	00h
0255h	UART1 Special Mode Register 3	U1SMR3	000X 0X0Xb
0256h	UART1 Special Mode Register 2	U1SMR2	X000 0000b
0257h	UART1 Special Mode Register	U1SMR	X000 0000b
0258h	UART1 Transmit/Receive Mode Register	U1MR	00h
0259h	UART1 Bit Rate Register	U1BRG	XXh
025Ah	UART1 Transmit Buffer Register	U1TB	XXh
025Bh			XXh
025Ch	UART1 Transmit/Receive Control Register 0	U1C0	0000 1000b
025Dh	UART1 Transmit/Receive Control Register 1	U1C1	00XX 0010b
025Eh	UART1 Receive Buffer Register	U1RB	XXh
025Fh			XXh
0260h			
0261h			
0262h			
0263h			
0264h	UART2 Special Mode Register 4	U2SMR4	00h
0265h	UART2 Special Mode Register 3	U2SMR3	000X 0X0Xb
0266h	UART2 Special Mode Register 2	U2SMR2	X000 0000b
0267h	UART2 Special Mode Register	U2SMR	X000 0000b
0268h	UART2 Transmit/Receive Mode Register	U2MR	00h
0269h	UART2 Bit Rate Register	U2BRG	XXh
026Ah	UART2 Transmit Buffer Register	U2TB	XXh
026Bh			XXh
026Ch	UART2 Transmit/Receive Control Register 0	U2C0	0000 1000b
026Dh	UART2 Transmit/Receive Control Register 1	U2C1	0000 0010b
026Eh	UART2 Receive Buffer Register	U2RB	XXh
026Fh			XXh

X: Undefined

Note:

1. The blank areas are reserved. No access is allowed.

Table 4.12 SFR Information (12) ⁽¹⁾

Address	Register	Symbol	Reset Value
0300h	Timer B3/B4/B5 Count Start Flag	TBSR	000X XXXXb
0301h			
0302h	Timer A1-1 Register	TA11	XXh
0303h			XXh
0304h	Timer A2-1 Register	TA21	XXh
0305h			XXh
0306h	Timer A4-1 Register	TA41	XXh
0307h			XXh
0308h	Three-Phase PWM Control Register 0	INVC0	00h
0309h	Three-Phase PWM Control Register 1	INVC1	00h
030Ah	Three-Phase Output Buffer Register 0	IDB0	XX11 1111b
030Bh	Three-Phase Output Buffer Register 1	IDB1	XX11 1111b
030Ch	Dead Time Timer	DTT	XXh
030Dh	Timer B2 Interrupt Generation Frequency Set Counter	ICTB2	XXh
030Eh	Position-Data-Retain Function Control Register	PDRF	XXXX 0000b
030Fh			
0310h	Timer B3 Register	TB3	XXh
0311h			XXh
0312h	Timer B4 Register	TB4	XXh
0313h			XXh
0314h	Timer B5 Register	TB5	XXh
0315h			XXh
0316h			
0317h			
0318h	Port Function Control Register	PFCR	0011 1111b
0319h			
031Ah			
031Bh	Timer B3 Mode Register	TB3MR	00XX 0000b
031Ch	Timer B4 Mode Register	TB4MR	00XX 0000b
031Dh	Timer B5 Mode Register	TB5MR	00XX 0000b
031Eh			
031Fh			
0320h	Count Start Flag	TABSR	00h
0321h			
0322h	One-Shot Start Flag	ONSF	00h
0323h	Trigger Select Register	TRGSR	00h
0324h	Increment/Decrement Flag	UDF	00h
0325h			
0326h	Timer A0 Register	TA0	XXh
0327h			XXh
0328h	Timer A1 Register	TA1	XXh
0329h			XXh
032Ah	Timer A2 Register	TA2	XXh
032Bh			XXh
032Ch	Timer A3 Register	TA3	XXh
032Dh			XXh
032Eh	Timer A4 Register	TA4	XXh
032Fh			XXh

X: Undefined

Note:

1. The blank areas are reserved. No access is allowed.

Table 4.15 SFR Information (15) ⁽¹⁾

Address	Register	Symbol	Reset Value
0390h	DMA2 Source Select Register	DM2SL	00h
0391h			
0392h	DMA3 Source Select Register	DM3SL	00h
0393h			
0394h			
0395h			
0396h			
0397h			
0398h	DMA0 Source Select Register	DM0SL	00h
0399h			
039Ah	DMA1 Source Select Register	DM1SL	00h
039Bh			
039Ch			
039Dh			
039Eh			
039Fh			
03A0h			
03A1h			
03A2h	Open-Circuit Detection Assist Function Register	AINRST	XX00 XXXXb
03A3h			
03A4h			
03A5h			
03A6h			
03A7h			
03A8h			
03A9h			
03AAh			
03ABh			
03ACh			
03ADh			
03AEh			
03AFh			
03B0h			
03B1h			
03B2h			
03B3h			
03B4h	SFR Snoop Address Register	CRCSAR	XXXX XXXXb
03B5h			00XX XXXXb
03B6h	CRC Mode Register	CRCMR	0XXX XXX0b
03B7h			
03B8h			
03B9h			
03BAh			
03BBh			
03BCh	CRC Data Register	CRCD	XXh
03BDh			XXh
03BEh	CRC Input Register	CRCIN	XXh
03BFh			

X: Undefined

Note:

1. The blank areas are reserved. No access is allowed.

5.1.5 Flash Memory Electrical Characteristics

Table 5.9 CPU Clock When Operating Flash Memory (f_{BCLK})

$V_{\text{CC1}} = 1.8$ to 5.5 V, $T_{\text{opr}} = -20^{\circ}\text{C}$ to $85^{\circ}\text{C}/-40^{\circ}\text{C}$ to 85°C unless otherwise specified.

Symbol	Parameter	Conditions	Standard			Unit
			Min.	Typ.	Max.	
-	CPU rewrite mode				10 (1)	MHz
$f(\text{SLOW_R})$	Slow read mode				5 (3)	MHz
-	Low current consumption read mode			$f_{\text{C}}(32.768)$	35	kHz
-	Data flash read	$3.0\text{ V} < V_{\text{CC1}} \leq 5.5\text{ V}$			20 (2)	MHz

Notes:

- Set the PM17 bit in the PM1 register to 1 (one wait).
- When the frequency is $1.8 \leq V_{\text{CC1}} \leq 3.0$ V, set the FMR17 bit in the FMR1 register to 0 (one wait) or the PM17 bit in the PM1 register to 1 (one wait).
- Set the PM17 bit in the PM1 register to 1 (one wait). When using 125 kHz on-chip oscillator clock or sub clock as the CPU clock source, a wait is not necessary.

Table 5.10 Flash Memory (Program ROM 1, 2) Electrical Characteristics

$V_{\text{CC1}} = 2.7$ to 5.5 V at $T_{\text{opr}} = 0^{\circ}\text{C}$ to 60°C (option: -40°C to 85°C), unless otherwise specified.

Symbol	Parameter	Conditions	Standard			Unit
			Min.	Typ.	Max.	
-	Program and erase cycles (1), (3), (4)	$V_{\text{CC1}} = 3.3\text{ V}$, $T_{\text{opr}} = 25^{\circ}\text{C}$	1,000 (2)			times
-	2 word program time	$V_{\text{CC1}} = 3.3\text{ V}$, $T_{\text{opr}} = 25^{\circ}\text{C}$		150	4000	μs
-	Lock bit program time	$V_{\text{CC1}} = 3.3\text{ V}$, $T_{\text{opr}} = 25^{\circ}\text{C}$		70	3000	μs
-	Block erase time	$V_{\text{CC1}} = 3.3\text{ V}$, $T_{\text{opr}} = 25^{\circ}\text{C}$		0.2	3.0	s
$t_{\text{d}}(\text{SR-SUS})$	Time delay from suspend request until suspend				$5 + \frac{3}{f_{\text{BCLK}}}$	ms
-	Interval from erase start/restart until following suspend request		0			μs
-	Suspend interval necessary for auto-erasure to complete (7)		20			ms
-	Time from suspend until erase restart				$30 + \frac{1}{f_{\text{BCLK}}}$	μs
-	Program, erase voltage		2.7		5.5	V
-	Read voltage	$T_{\text{opr}} = -20^{\circ}\text{C}$ to $85^{\circ}\text{C}/-40^{\circ}\text{C}$ to 85°C	2.7		5.5	V
-	Program, erase temperature		0		60	$^{\circ}\text{C}$
t_{PS}	Flash memory circuit stabilization wait time				50	μs
-	Data hold time (6)	Ambient temperature = 55°C	20			year

Notes:

- Definition of program and erase cycles:
The program and erase cycles refer to the number of per-block erasures. If the program and erase cycles are n ($n = 1,000$), each block can be erased n times. For example, if a block is erased after writing 2 word data 16,384 times, each to a different address, this counts as one program and erase cycles. Data cannot be written to the same address more than once without erasing the block (rewrite prohibited).
- Cycles to guarantee all electrical characteristics after program and erase. (1 to Min. value can be guaranteed).
- In a system that executes multiple programming operations, the actual erasure count can be reduced by writing to sequential addresses in turn so that as much of the block as possible is used up before performing an erase operation. It is advisable to retain data on the erasure cycles of each block and limit the number of erase operations to a certain number.
- If an error occurs during block erase, attempt to execute the clear status register command, then execute the block erase command at least three times until the erase error does not occur.
- Customers desiring program/erase failure rate information should contact a Renesas Electronics sales office.
- The data hold time includes time that the power supply is off or the clock is not supplied.
- After an erase start or erase restart, if an interval of at least 20 ms is not set before the next suspend request, the erase sequence cannot be completed.

Table 5.11 Flash Memory (Data Flash) Electrical Characteristics

$V_{CC1} = 2.7$ to 5.5 V at $T_{opr} = -20$ to $85^{\circ}\text{C}/-40$ to 85°C , unless otherwise specified.

Symbol	Parameter	Conditions	Standard			Unit
			Min.	Typ.	Max.	
-	Program and erase cycles (1), (3), (4)	$V_{CC1} = 3.3$ V, $T_{opr} = 25^{\circ}\text{C}$	10,000 (2)			times
-	2 word program time	$V_{CC1} = 3.3$ V, $T_{opr} = 25^{\circ}\text{C}$		300	4000	μs
-	Lock bit program time	$V_{CC1} = 3.3$ V, $T_{opr} = 25^{\circ}\text{C}$		140	3000	μs
-	Block erase time	$V_{CC1} = 3.3$ V, $T_{opr} = 25^{\circ}\text{C}$		0.2	3.0	s
$t_{d(SR-SUS)}$	Time delay from suspend request until suspend				$5 + \frac{3}{f_{(BCLK)}}$	ms
-	Interval from erase start/restart until following suspend request		0			μs
-	Suspend interval necessary for auto-erase to complete (7)		20			ms
-	Time from suspend until erase restart				$30 + \frac{1}{f_{(BCLK)}}$	μs
-	Program, erase voltage		2.7		5.5	V
-	Read voltage		2.7		5.5	V
-	Program, erase temperature		-20/-40		85	$^{\circ}\text{C}$
t_{PS}	Flash memory circuit stabilization wait time				50	μs
-	Data hold time (6)	Ambient temperature = 55°C	20			year

Notes:

- Definition of program and erase cycles
The program and erase cycles refer to the number of per-block erasures.
If the program and erase cycles are n ($n = 10,000$), each block can be erased n times.
For example, if a 4 KB block is erased after writing 2 word data 1,024 times, each to a different address, this counts as one program and erase cycles. Data cannot be written to the same address more than once without erasing the block (rewrite prohibited).
- Cycles to guarantee all electrical characteristics after program and erase. (1 to Min. value can be guaranteed).
- In a system that executes multiple programming operations, the actual erasure count can be reduced by writing to sequential addresses in turn so that as much of the block as possible is used up before performing an erase operation. For example, when programming groups of 16 bytes, the effective number of rewrites can be minimized by programming up to 256 groups before erasing them all in one operation. In addition, averaging the erasure cycles between blocks A and B can further reduce the actual erasure cycles. It is also advisable to retain data on the erasure cycles of each block and limit the number of erase operations to a certain number.
- If an error occurs during block erase, attempt to execute the clear status register command, then execute the block erase command at least three times until the erase error does not occur.
- Customers desiring program/erase failure rate information should contact a Renesas Electronics sales office.
- The data hold time includes time that the power supply is off or the clock is not supplied.
- After an erase start or erase restart, if an interval of at least 20 ms is not set before the next suspend request, the erase sequence cannot be completed.

Table 5.14 Voltage Detector 2 Electrical Characteristics

The measurement condition is $V_{CC1} = 1.8$ to 5.5 V, $T_{opr} = -20^{\circ}\text{C}$ to $85^{\circ}\text{C}/-40^{\circ}\text{C}$ to 85°C , unless otherwise specified.

Symbol	Parameter	Condition	Standard			Unit
			Min.	Typ.	Max.	
V_{det2}	Voltage detection level V_{det2_0}	When V_{CC1} is falling	3.70	4.00	4.30	V
-	Hysteresis width at the rising of V_{CC1} in voltage detector 2			0.15		V
-	Voltage detector 2 response time ⁽²⁾	When V_{CC1} falls from 5 V to $(V_{det2_0} - 0.1)$ V			200	μs
-	Voltage detector self power consumption	$VC27 = 1$, $V_{CC1} = 5.0$ V		1.7		μA
$t_{d(E-A)}$	Waiting time until voltage detector operation starts ⁽¹⁾				100	μs

Notes:

- Necessary time until the voltage detector operates after setting to 1 again after setting the VC27 bit in the VCR2 register to 0.
- Time from when passing the V_{det2} until when a voltage monitor 2 reset is generated.

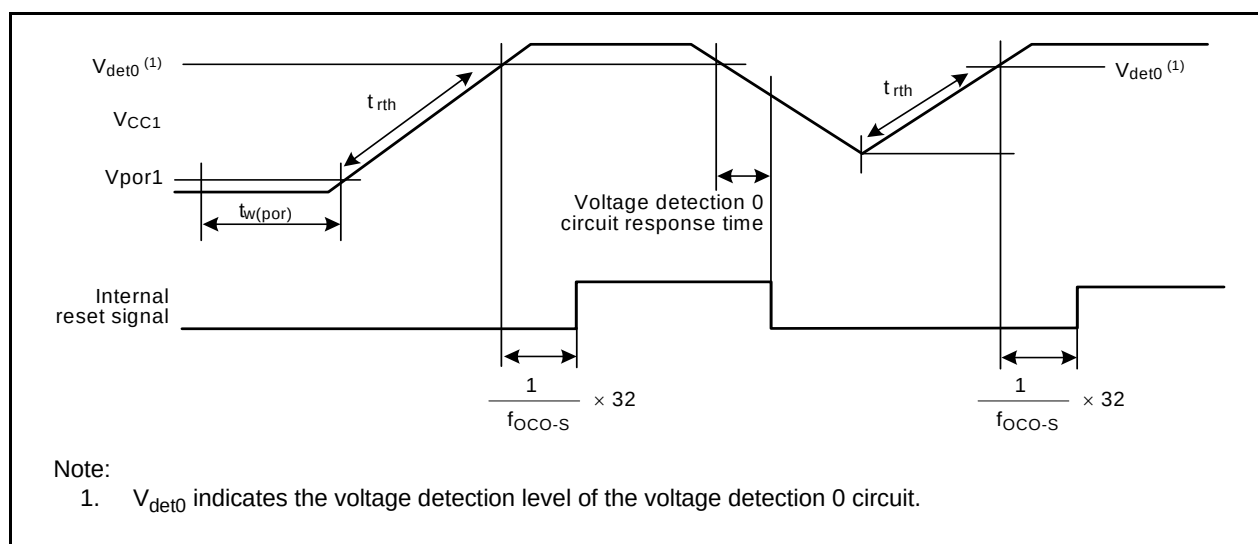
Table 5.15 Power-On Reset Circuit

The measurement condition is $V_{CC1} = 2.0$ to 5.5 V, $T_{opr} = -20^{\circ}\text{C}$ to $85^{\circ}\text{C}/-40^{\circ}\text{C}$ to 85°C , unless otherwise specified.

Symbol	Parameter	Condition	Standard			Unit
			Min.	Typ.	Max.	
V_{por1}	Voltage at which power-on reset enabled ⁽¹⁾				0.5	V
t_{rth}	External power V_{CC1} rise gradient		2.0		50000	mV/ms
$t_{w(por)}$	Time necessary to enable power-on reset		300			ms

Note:

- To use the power-on reset function, enable voltage monitor 0 reset by setting the LVDAS bit in the OFS1 address to 0. Also, set the VDSEL1 bit to 0 (V_{det0_2}).

**Figure 5.4 Power-On Reset Circuit Electrical Characteristics**

$$V_{CC1} = V_{CC2} = 5 \text{ V}$$

5.2.2 Timing Requirements (Peripheral Functions and Others)

($V_{CC1} = V_{CC2} = 5 \text{ V}$, $V_{SS} = 0 \text{ V}$, at $T_{opr} = -20^{\circ}\text{C}$ to 85°C / -40°C to 85°C unless otherwise specified)

5.2.2.1 Reset Input ($\overline{\text{RESET}}$ Input)

Table 5.22 Reset Input ($\overline{\text{RESET}}$ Input)

Symbol	Parameter	Standard		Unit
		Min.	Max.	
$t_{w(RSTL)}$	$\overline{\text{RESET}}$ input low pulse width	10		μs

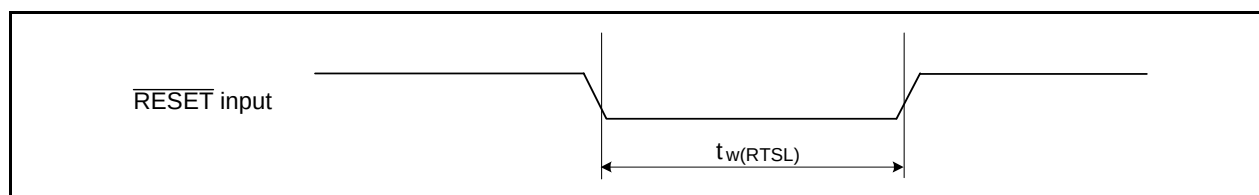


Figure 5.6 Reset Input ($\overline{\text{RESET}}$ Input)

5.2.2.2 External Clock Input

Table 5.23 External Clock Input (XIN Input) (1)

Symbol	Parameter	Standard		Unit
		Min.	Max.	
t_c	External clock input cycle time	50		ns
$t_{w(H)}$	External clock input high pulse width	20		ns
$t_{w(L)}$	External clock input low pulse width	20		ns
t_r	External clock rise time		9	ns
t_f	External clock fall time		9	ns

Note:

- The condition is $V_{CC1} = V_{CC2} = 3.0$ to 5.0 V .

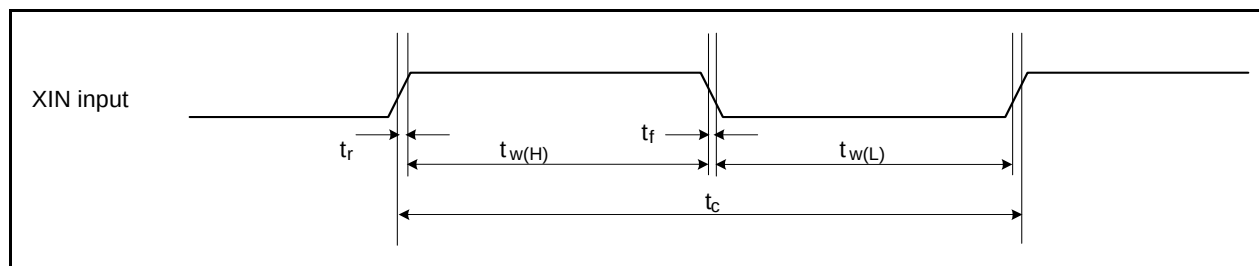


Figure 5.7 External Clock Input (XIN Input)

$$V_{CC1} = V_{CC2} = 5\text{ V}$$

Timing Requirements

($V_{CC1} = V_{CC2} = 5\text{ V}$, $V_{SS} = 0\text{ V}$, at $T_{opr} = -20^{\circ}\text{C}$ to $85^{\circ}\text{C}/-40^{\circ}\text{C}$ to 85°C unless otherwise specified)

5.2.2.5 Serial Interface

Table 5.32 Serial Interface

Symbol	Parameter	Standard		Unit
		Min.	Max.	
$t_c(\text{CK})$	CLKi input cycle time	200		ns
$t_w(\text{CKH})$	CLKi input high pulse width	100		ns
$t_w(\text{CKL})$	CLKi input low pulse width	100		ns
$t_d(\text{C-Q})$	TXDi output delay time		80	ns
$t_h(\text{C-Q})$	TXDi hold time	0		ns
$t_{su}(\text{D-C})$	RXDi input setup time	70		ns
$t_h(\text{C-D})$	RXDi input hold time	90		ns

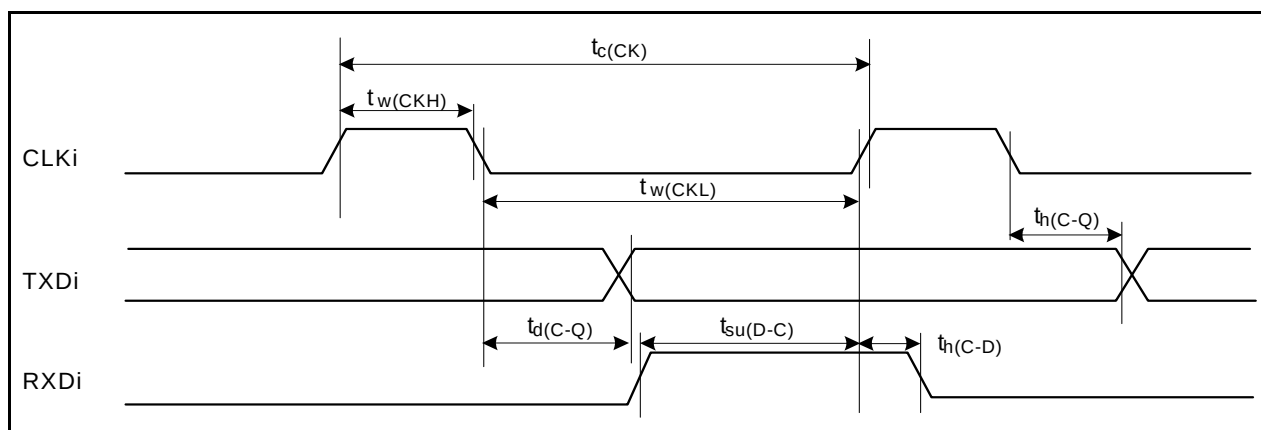


Figure 5.11 Serial Interface

5.2.2.6 External Interrupt $\overline{\text{INTi}}$ Input

Table 5.33 External Interrupt $\overline{\text{INTi}}$ Input

Symbol	Parameter	Standard		Unit
		Min.	Max.	
$t_w(\text{INH})$	$\overline{\text{INTi}}$ input high pulse width	250		ns
$t_w(\text{INL})$	$\overline{\text{INTi}}$ input low pulse width	250		ns

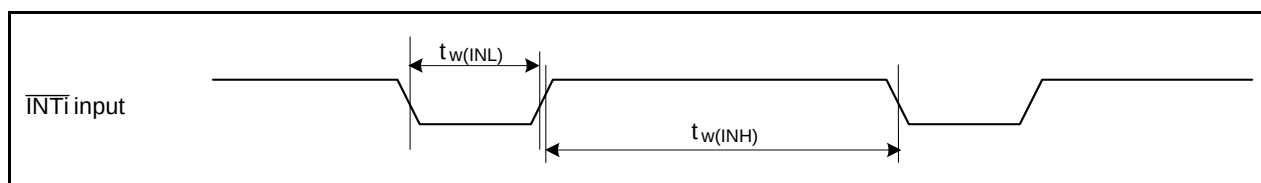


Figure 5.12 External Interrupt $\overline{\text{INTi}}$ Input

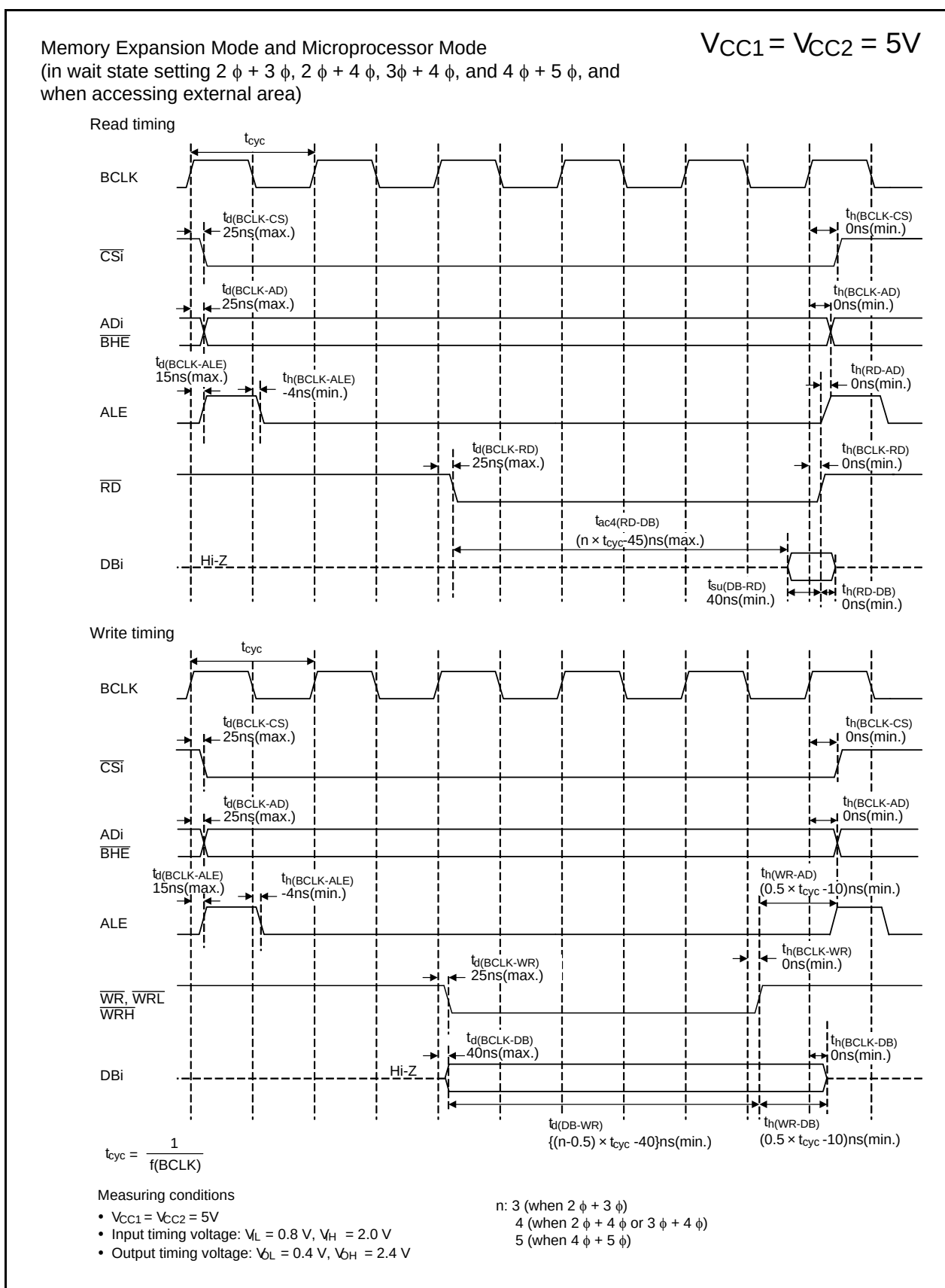


Figure 5.19 Timing Diagram

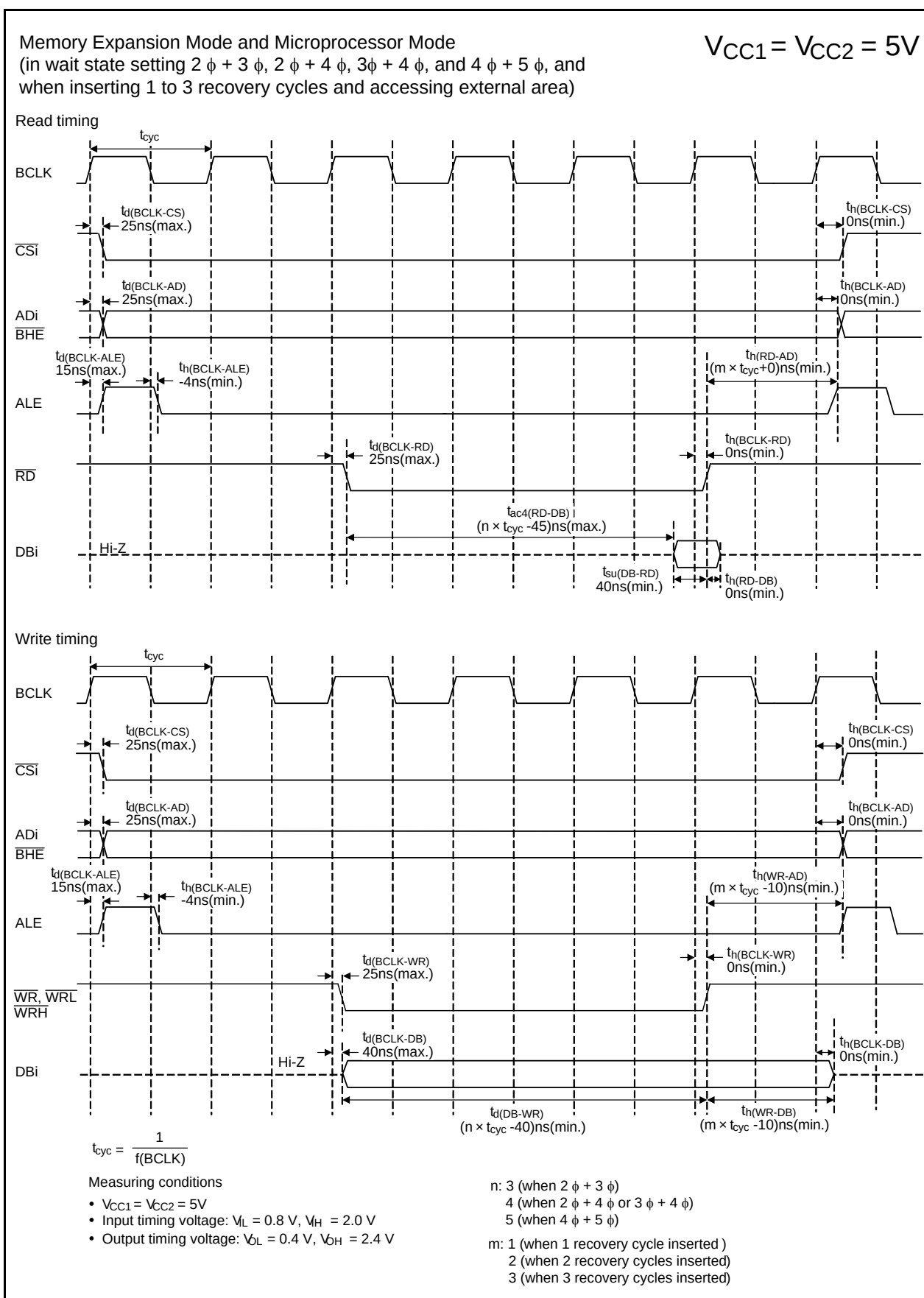


Figure 5.20 Timing Diagram

$$V_{CC1} = V_{CC2} = 3 \text{ V}$$

Table 5.42 Electrical Characteristics (2)
 $V_{CC1} = V_{CC2} = 2.7 \text{ to } 3.3 \text{ V}$, $V_{SS} = 0 \text{ V}$ at $T_{opr} = -20^{\circ}\text{C}$ to 85°C / -40°C to 85°C , $f_{(BCLK)} = 20 \text{ MHz}$ unless otherwise specified.

Symbol	Parameter	Measuring Condition	Standard			Unit
			Min.	Typ.	Max.	
I_{CC}	Power supply current In single-chip, mode, the output pin are open and other pins are V_{SS}	High-speed mode	$f_{(BCLK)} = 20 \text{ MHz}$ (no division) XIN = 20 MHz (square wave) 125 kHz on-chip oscillator stopped CM15 = 1 (drive capacity High) A/D converter stopped	9.5		mA
			$f_{(BCLK)} = 20 \text{ MHz}$ (no division) XIN = 20 MHz (square wave) 125 kHz on-chip oscillator stopped CM15 = 1 (drive capacity High) A/D converter operating ⁽²⁾	10.2		mA
			$f_{(BCLK)} = 20 \text{ MHz}$ XIN = 20 MHz (square wave) 125 kHz on-chip oscillator stopped CM15 = 0 (drive capacity Low) A/D converter stopped	9.2		mA
			$f_{(BCLK)} = 20 \text{ MHz}$ (no division) XIN = 20 MHz (square wave) 125 kHz on-chip oscillator stopped CM15 = 1 (drive capacity High) PCLKSTP1 = FF (peripheral clock stopped)	7.9		mA
			$f_{(BCLK)} = 20 \text{ MHz}$ (no division) XIN = 20 MHz (square wave) 125 kHz on-chip oscillator stopped CM15 = 0 (drive capacity Low) PCLKSTP1 = FF (peripheral clock stopped)	7.6		mA
		40 MHz on-chip oscillator mode	Main clock stopped 40 MHz on-chip oscillator on, divide-by-2 ($f_{(BCLK)} = 20 \text{ MHz}$) 125 kHz on-chip oscillator stopped	9.0		mA
		125 kHz on-chip oscillator mode	Main clock stopped 40 MHz on-chip oscillator stopped 125 kHz on-chip oscillator on, no division FMR22 = 1 (slow read mode)	450.0		μA
		Low-power mode	$f_{(BCLK)} = 32 \text{ MHz}$ FMR 22 = FMR23 = 1 (in low-current consumption read mode) On flash memory ⁽¹⁾	80.0		μA
		Wait mode	$f_{(BCLK)} = 32 \text{ kHz}$ Main clock stopped 40 MHz on-chip oscillator stopped 125 kHz on-chip oscillator on PM25 = 1 (peripheral function clock fC operating) $T_{opr} = 25^{\circ}\text{C}$ Real-time clock operating	5.3		μA
			$f_{(BCLK)} = 32 \text{ MHz}$ 40 MHz on-chip oscillator stopped 125 kHz on-chip oscillator stopped PM25 = 0 (peripheral function clock fC stopped) $T_{opr} = 25^{\circ}\text{C}$	5.0		μA
		Stop mode	$T_{opr} = 25^{\circ}\text{C}$	2.2		μA
		During flash memory program	$f_{(BCLK)} = 10 \text{ MHz}$, PM17 = 1 (one wait) $V_{CC1} = 3.0 \text{ V}$	20.0		mA
		During flash memory erase	$f_{(BCLK)} = 10 \text{ MHz}$, PM17 = 1 (one wait) $V_{CC1} = 3.0 \text{ V}$	30.0		mA

Notes:

1. This indicates the memory in which the program to be executed exists.
2. A/D conversion is executed in repeat mode.

$$V_{CC1} = V_{CC2} = 3 \text{ V}$$

5.3.2 Timing Requirements (Peripheral Functions and Others)

($V_{CC1} = V_{CC2} = 3 \text{ V}$, $V_{SS} = 0 \text{ V}$, at $T_{opr} = -20^{\circ}\text{C}$ to 85°C / -40°C to 85°C unless otherwise specified)

5.3.2.1 Reset Input ($\overline{\text{RESET}}$ Input)

Table 5.43 Reset Input ($\overline{\text{RESET}}$ Input)

Symbol	Parameter	Standard		Unit
		Min.	Max.	
$t_{w(RSTL)}$	$\overline{\text{RESET}}$ input low pulse width	10		μs

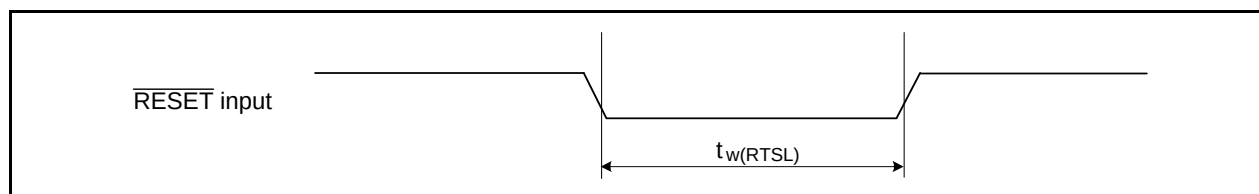


Figure 5.21 Reset Input ($\overline{\text{RESET}}$ Input)

5.3.2.2 External Clock Input

Table 5.44 External Clock Input (XIN Input) (1)

Symbol	Parameter	Standard		Unit
		Min.	Max.	
t_c	External clock input cycle time	50		ns
$t_{w(H)}$	External clock input high pulse width	20		ns
$t_{w(L)}$	External clock input low pulse width	20		ns
t_r	External clock rise time		9	ns
t_f	External clock fall time		9	ns

Note:

1. The condition is $V_{CC1} = V_{CC2} = 2.7$ to 3.0 V .

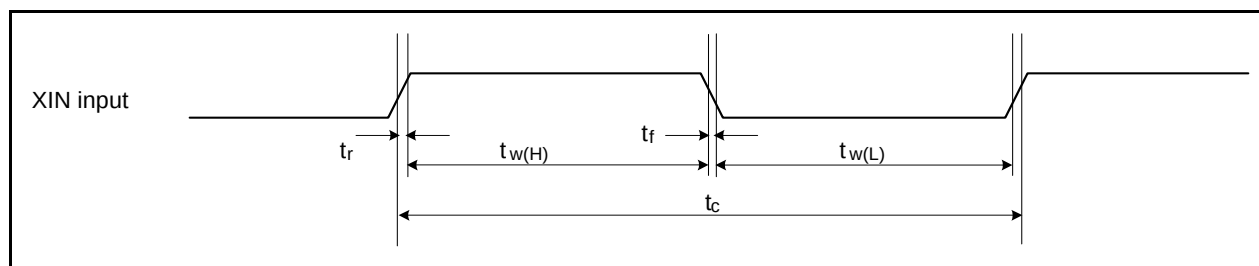


Figure 5.22 External Clock Input (XIN Input)

$$V_{CC1} = V_{CC2} = 3\text{ V}$$

Timing Requirements

($V_{CC1} = V_{CC2} = 3\text{ V}$, $V_{SS} = 0\text{ V}$, at $T_{opr} = -20^{\circ}\text{C}$ to $85^{\circ}\text{C}/-40^{\circ}\text{C}$ to 85°C unless otherwise specified)

5.3.2.4 Timer B Input**Table 5.50 Timer B Input (Counter Input in Event Counter Mode)**

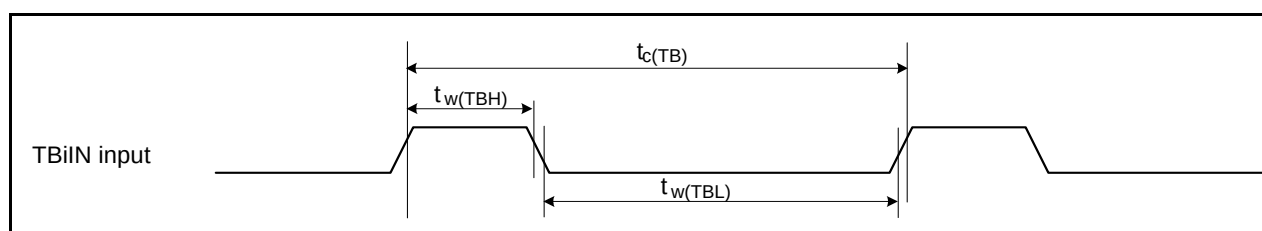
Symbol	Parameter	Standard		Unit
		Min.	Max.	
$t_{c(TB)}$	TBiIN input cycle time (counted on one edge)	150		ns
$t_{w(TBH)}$	TBiIN input high pulse width (counted on one edge)	60		ns
$t_{w(TBL)}$	TBiIN input low pulse width (counted on one edge)	60		ns
$t_{c(TB)}$	TBiIN input cycle time (counted on both edges)	300		ns
$t_{w(TBH)}$	TBiIN input high pulse width (counted on both edges)	120		ns
$t_{w(TBL)}$	TBiIN input low pulse width (counted on both edges)	120		ns

Table 5.51 Timer B Input (Pulse Period Measurement Mode)

Symbol	Parameter	Standard		Unit
		Min.	Max.	
$t_{c(TB)}$	TBiIN input cycle time	600		ns
$t_{w(TBH)}$	TBiIN input high pulse width	300		ns
$t_{w(TBL)}$	TBiIN input low pulse width	300		ns

Table 5.52 Timer B Input (Pulse Width Measurement Mode)

Symbol	Parameter	Standard		Unit
		Min.	Max.	
$t_{c(TB)}$	TBiIN input cycle time	600		ns
$t_{w(TBH)}$	TBiIN input high pulse width	300		ns
$t_{w(TBL)}$	TBiIN input low pulse width	300		ns

**Figure 5.25 Timer B Input**

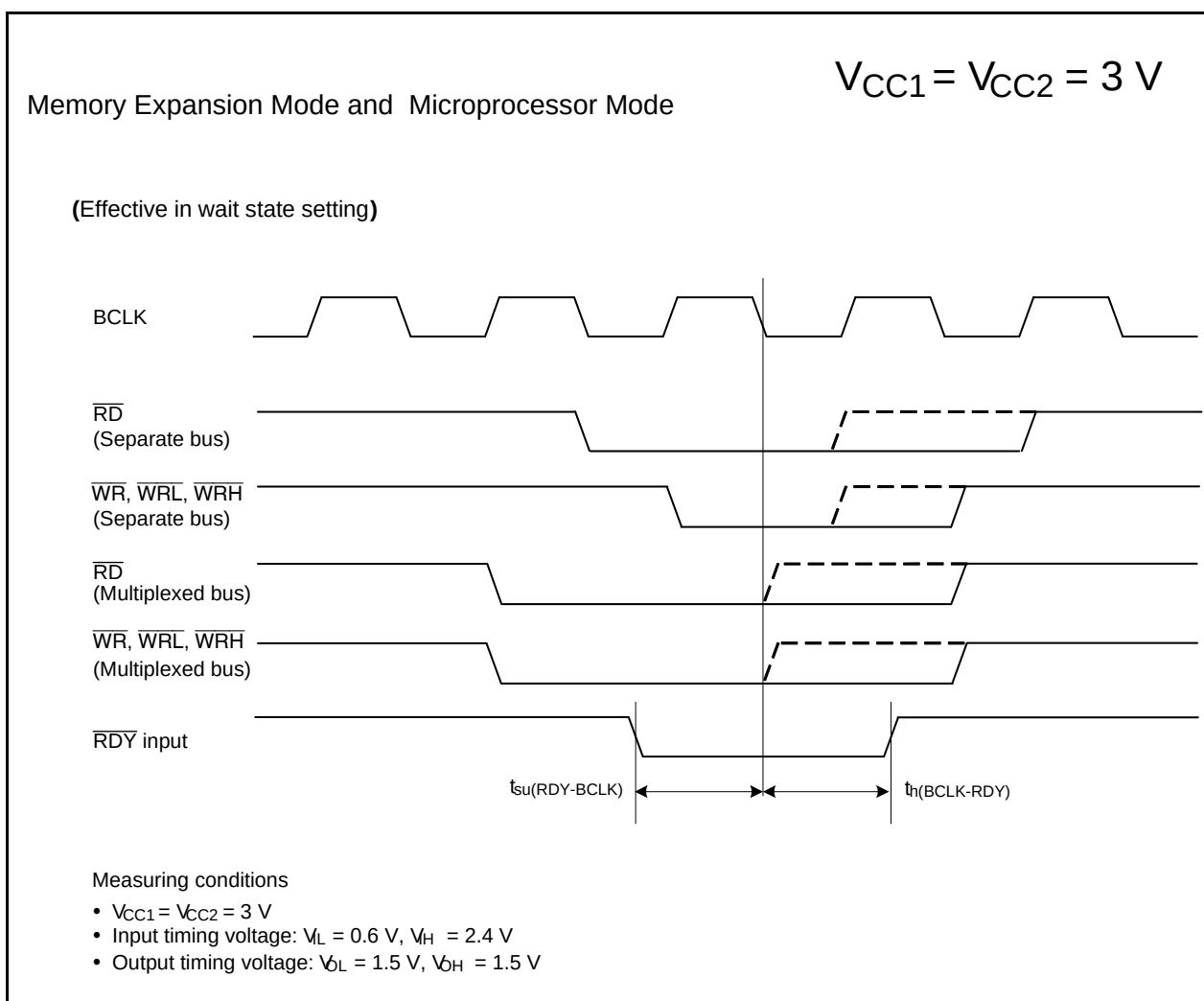


Figure 5.29 Timing Diagram

$$V_{CC1} = V_{CC2} = 3 \text{ V}$$

Switching Characteristics

($V_{CC1} = V_{CC2} = 3 \text{ V}$, $V_{SS} = 0 \text{ V}$, at $T_{opr} = -20^{\circ}\text{C}$ to 85°C / -40°C to 85°C unless otherwise specified)

5.3.4.2 In 1 to 3 Waits Setting and When Accessing External Area

Table 5.58 Memory Expansion Mode and Microprocessor Mode (in 1 to 3 Waits Setting and When Accessing External Area)

Symbol	Parameter	Measuring Condition	Standard		Unit
			Min.	Max.	
$t_{d(BCLK-AD)}$	Address output delay time	See Figure 5.30		30	ns
$t_{h(BCLK-AD)}$	Address output hold time (in relation to BCLK)		0		ns
$t_{h(RD-AD)}$	Address output hold time (in relation to RD)		0		ns
$t_{h(WR-AD)}$	Address output hold time (in relation to WR)		(Note 2)		ns
$t_{d(BCLK-CS)}$	Chip select output delay time			30	ns
$t_{h(BCLK-CS)}$	Chip select output hold time (in relation to BCLK)		0		ns
$t_{d(BCLK-ALE)}$	ALE signal output delay time			25	ns
$t_{h(BCLK-ALE)}$	ALE signal output hold time		-4		ns
$t_{d(BCLK-RD)}$	RD signal output delay time			30	ns
$t_{h(BCLK-RD)}$	RD signal output hold time		0		ns
$t_{d(BCLK-WR)}$	WR signal output delay time			30	ns
$t_{h(BCLK-WR)}$	WR signal output hold time		0		ns
$t_{d(BCLK-DB)}$	Data output delay time (in relation to BCLK)			40	ns
$t_{h(BCLK-DB)}$	Data output hold time (in relation to BCLK) ⁽³⁾		0		ns
$t_{d(DB-WR)}$	Data output delay time (in relation to WR)		(Note 1)		ns
$t_{h(WR-DB)}$	Data output hold time (in relation to WR) ⁽³⁾		(Note 2)		ns

Notes:

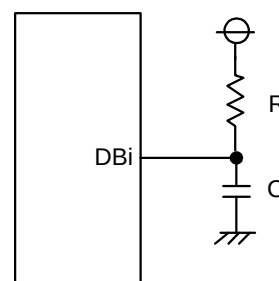
1. Calculated according to the BCLK frequency as follows:

$$\frac{(n - 0.5) \times 10^9}{f_{(BCLK)}} - 40 [ns] \quad \begin{array}{l} n \text{ is 1 for 1 wait setting, 2 for 2 waits setting and 3 for 3 waits setting.} \\ \text{When } n = 1, f_{(BCLK)} \text{ is 12.5 MHz or less.} \end{array}$$

2. Calculated according to the BCLK frequency as follows:

$$\frac{0.5 \times 10^9}{f_{(BCLK)}} - 10 [ns]$$

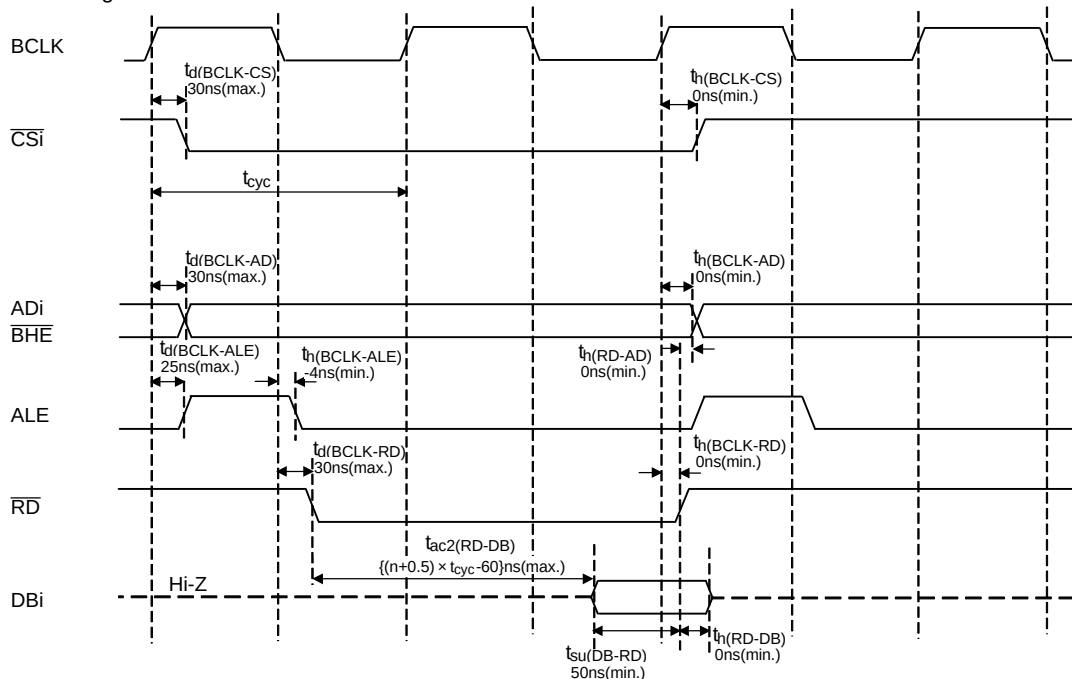
3. This standard value shows the timing when the output is off, and does not show hold time of data bus.
Hold time of data bus varies with capacitor volume and pull-up (pull-down) resistance value.
Hold time of data bus is expressed in
 $t = -CR \times \ln(1 - V_{OL}/V_{CC2})$
by a circuit of the right figure.
For example, when $V_{OL} = 0.2V_{CC2}$, $C = 30 \text{ pF}$, $R = 1 \text{ k}\Omega$, hold time of output low level is
 $t = -30 \text{ pF} \times 1 \text{ k}\Omega \times \ln(1 - 0.2V_{CC2}/V_{CC2})$
 $= 6.7 \text{ ns}$.



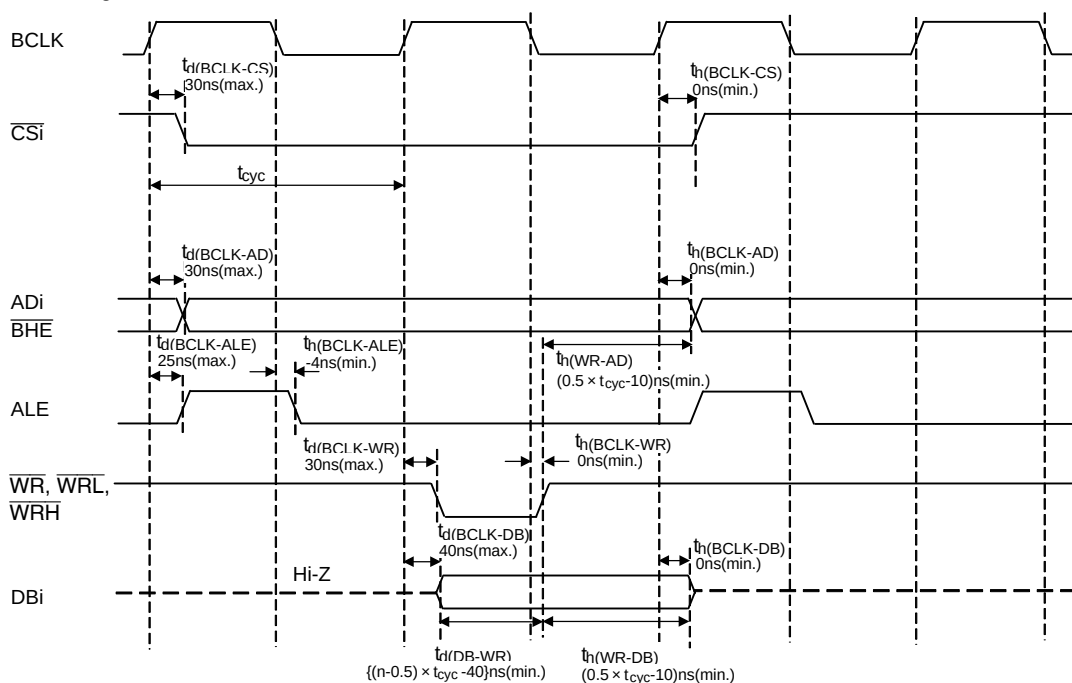
Memory Expansion Mode and Microprocessor Mode
(in 1 to 3 waits setting and when accessing external area)

$$V_{CC1} = V_{CC2} = 3V$$

Read timing



Write timing



$$t_{cyc} = \frac{1}{f(\text{BCLK})}$$

Measuring conditions

- $V_{CC1} = V_{CC2} = 3V$
- Input timing voltage: $V_L = 0.6V$, $V_H = 2.4V$
- Output timing voltage: $V_L = 1.5V$, $V_H = 1.5V$

n: 1 (when 1 wait)
2 (when 2 waits)
3 (when 3 waits)

Figure 5.32 Timing Diagram